

Application/Control No. 10/646,555	Applicant(s)/Patent under Reexamination LEE ET AL.
Examiner	Art Unit
Charles Kim	2624

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	•	ORIGINAL			INTERNATIONAL CLASSIFICATION										
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	Claims renumbered in the same order as presented by applicant								□СРА			☐ T.D.			☐ R.1.47				
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
1	1			31			61			91			121			151			181
2	2			32			62]		92			122			152			182
3	3			33			63]		93			123			153			183
	4			34			64			94			124			154			184
4	5			35			65]		95			125			155			185
5	6			36			66			96			126			156			186
	7			37			67]		97			127			157			187
	8			38			68			98			128			158			188
	9			39.			69]		99			129			159			189
6	10			40			70			100			130			160			190
7	11			41			71			101			131			161			191
	12	Ì		42			72			102			132			162			192
	13			43			73			103			133			163			193
8	14			44			74		·	104			134			164			194
9	15			45	1		75			105			135			165			195
	16			46			76]		106			136			166			196
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	18			48			78			108			138			168			198
	19	ĺ		49	1		79			109			139			169			199
	20			50			80			110			140			170		Ĺ	200
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	22			52	1		82			112			142			172			202
	23	1		53]		83			113			143			173			203
	24			54			84			114			144			174			204
	25			55]		85			115			145			175			205
	26			56			86			116			146			176			206
	27	1	-	57]		87			117	,		147			177			207
	28	1		58	1		88			118			148			178			208
	29	1		59			89			119			149			179			209
	30	<u> </u>		60			90			120			150	<u></u>		180_		L	210